| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
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| S1 | 826 | @ad<="20040329" and (257/328).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:24 |
| S2 | 219 | @ad<="20040329" and (438/212).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 06:48 |
| S3 | 635 | @ad<="20040329" and (438/268).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 06:49 |
| S4 | 1908 | @ad<="20040329" and (257/355-356).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 06:50 |
| S5 | 463 | @ad<="20040329" and (257/357).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 06:51 |
| S6 | 58 | 'NEC' and 'ando takeshi' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 06:51 |
| S7 | 1954 | @ad<="20040329" and (257/369).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 06:53 |
| S8 | 2215 | @ad<="20040329" and 'CMOS' same 'protection' same 'circuit' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:37 |
| S9 | 1296 | @ad<="20040329" and 'CMOS' with 'protection' with 'circuit' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:02 |
| S10 | 777 | @ad<="20040329" and 'CMOS' with 'protection circuit' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:02 |

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| S11 | 3 | @ad<="20040329" and 'CMOS' with 'protection circuit' and 'output electrode' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:04 |
| S12 | 40 | @ad<="20040329" and 'CMOS' with 'protection' and 'surge' with 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 08:26 |
| S13 | 235 | @ad<="20040329" and 'CMOS' and 'protection' and 'surge' with 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:05 |
| S14 | 1150 | @ad<="20040329" and 'CMOS' and 'ESD' with 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:05 |
| S15 | 422 | @ad<="20040329" and 'CMOS' same 'ESD' with 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 09:43 |
| S16 | 283 | @ad<="20040329" and 'CMOS' with 'ESD' with 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:06 |
| S17 | 1833 | @ad<="20040329" and (361/56).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:49 |
| S18 | 1 | "6385028".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:24 |
| S19 | 1 | "6249410".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:25 |
| S20 | 1 | "6064249".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:26 |
| S21 | 1400 | @ad<="20040329" and (361/111).ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:41 |
| S22 | 1 | "6266222".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:28 |
| S23 | 1 | "6130811".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:28 |
| S24 | 1 | "6034397".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:29 |
| S25 | 1 | "6080612".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:33 |

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| S26 | 1 | "5963409".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:33 |
| S27 | 1 | "5086365".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:34 |
| S28 | 1 | "5910874".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:38 |
| S29 | 1 | "5729419".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:39 |
| S30 | 1 | "5644459".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:39 |
| S31 | 1 | "5086365".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:39 |
| S32 | 1 | "5644459".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:39 |
| S33 | 1 | "5499152".PN. | USPAT; USOCR | OR | ON | 2005/06/06 07:39 |
| S34 | 8 | @ad<="20040329" and 'Electrostatic damage protection circuit' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:44 |
| S36 | 1004 | @ad<="20040329" and 'ESD protection circuit' and 'CMOS' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:44 |
| S37 | 830 | @ad<="20040329" and 'ESD protection circuit' and 'CMOS' and 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:44 |
| S38 | 1 | @ad<="20040329" and 'ESD protection circuit' and 'CMOS' and 'output electrode' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 07:45 |
| S39 | 86 | @ad<="20040329" and 'CMOS' and 'protection transistor' and 'output transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:48 |
| S40 | 1 | "6066879".PN. | USPAT; USOCR | OR | ON | 2005/06/06 08:35 |
| S41 | 1 | "5918127".PN. | USPAT; USOCR | OR | ON | 2005/06/06 08:36 |
| S42 | 1 | "6080612".PN. | USPAT; USOCR | OR | ON | 2005/06/06 08:38 |
| S43 | 1 | "5610790".PN. | USPAT; USOCR | OR | ON | 2005/06/06 08:38 |
| S44 | 1 | "5986867".PN. | USPAT; USOCR | OR | ON | 2005/06/06 09:00 |

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| S45 | 1 | "5499152".PN. | USPAT; USOCR | OR | ON | 2005/06/06 09:00 |
| S46 | 1 | "6388315".PN. | USPAT; USOCR | OR | ON | 2005/06/06 09:12 |
| S47 | 1 | "6281554".PN. | USPAT; USOCR | OR | ON | 2005/06/06 09:12 |
| S48 | 1 | "6066879".PN. | USPAT; USOCR | OR | ON | 2005/06/06 09:38 |
| S49 | 1 | @ad<="20040329" and 'CMOS' and 'protection' and 'outout' and 'output pad' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 09:44 |
| S51 | 7 | @ad<="20040329" and 'CMOS' and 'protection MOS' and 'output MOS' and 'output pad' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 09:45 |
| S52 | 139 | @ad<="20040329" and 'CMOS' and 'protection' with 'MOS' and 'output' with 'MOS' and 'output pad' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:20 |
| S53 | 420 | @ad<="20040329" and 'CMOS' same 'output' same 'ESD' same 'protection' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:26 |
| S54 | 356 | @ad<="20040329" and 'CMOS' same 'output' same 'ESD protection' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:28 |
| S55 | 86 | @ad<="20040329" and 'CMOS' same 'output pad' same 'ESD protection' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:28 |
| S56 | 0 | @ad<="20040329" and 'CMOS' same 'output electrode' same 'ESD protection' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:29 |
| S57 | 2 | @ad<="20040329" and 'CMOS' and 'output electrode' and 'ESD protection' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:29 |
| S58 | 5 | @ad<="20040329" and 'CMOS' same 'protection' same 'circuit' and 'dummy transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:40 |

| S59 | 9 | 'Ichikawa Kenji' and 'oki' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:03 |
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| S60 | 2 | @ad<="20040329" and 'CMOS' and 'improved electrostatic breakdown resistance' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:44 |
| S61 | 23 | @ad<="20040329" and 'CMOS' and 'electrostatic breakdown resistance' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:44 |
| S62 | 76 | @ad<="20040329" and 'ESD' and 'protection transistor' and 'output transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 10:48 |
| S63 | 230 | Ichikawa-Kenji.in. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:05 |
| S64 | 3 | Ichikawa-Kenji.in. and 'ESD' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:04 |
| S65 | 13 | Ichikawa-Kenji.in. and 'semiconductor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:06 |
| S66 | 0 | 'surge current' same 'ON current' same 'protection transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:07 |
| S67 | 0 | 'surge current' and 'ON current' same 'protection transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:07 |
| S68 | 0 | 'surge current' and 'ON current' and 'protection transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:07 |
| S69 | 22 | 'surge current' same 'protection transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:13 |

| S70 | 1 | "6080612".PN. | USPAT; USOCR | OR | ON | 2005/06/06 11:11 |
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| S71 | 1 | 'protection transistor' and 'low' with ('electrostatic discharge' or 'ESD') with 'resistance' and 'electrode pad' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:15 |
| S72 | 51 | 'protection transistor' and 'low' with ('electrostatic discharge' or 'ESD') with 'resistance' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/06 11:15 |
| S73 | 411 | @ad<="20040329" and 'output' with ('electrode' or 'pad') and 'MOS' with 'protection' and 'MOS' with 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 10:15 |
| S74 | 21 | @ad<="20040329" and 'output' with ('electrode' or 'pad') and 'MOS' near 'protection' and 'MOS' near 'output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 08:14 |
| S75 | 1 | "6326666".PN. | USPAT; USOCR | OR | ON | 2005/06/07 08:37 |
| S76 | 1 | "6281554".PN. | USPAT; USOCR | OR | ON | 2005/06/07 08:38 |
| S77 | 1 | "6278160".PN. | USPAT; USOCR | OR | ON | 2005/06/07 08:39 |
| S78 | 1 | "6207996".PN. | USPAT; USOCR | OR | ON | 2005/06/07 08:39 |
| S79 | 70 | @ad<="20040329" and ('input/output' or 'I/O') and 'protection transistor' and 'output transistor' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 09:48 |
| S80 | 1 | @ad<="20040329" and ('input/output' or 'I/O') and 'MOS protection' and 'MOS output' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 09:22 |
| S81 | 10 | @ad<="20040329" and 'protection transistor' same 'gate' same 'connect' same 'substrate' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 09:28 |
| S82 | 1 | "6232220".PN. | USPAT; USOCR | OR | ON | 2005/06/07 09:32 |
| S83 | 8 | @ad<="20040329" and ('input/output' or 'I/O') and 'protection transistor' and 'positive surge' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 09:48 |

| S84 | 2 | "20040195625" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 10:00 |
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| S85 | 107 | @ad<="20040329" and 'CMOS' same 'protection' same 'SOI' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:03 |
| S86 | 84 | @ad<="20040329" and 'ESD protection' same 'SOI' same 'bulk' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:03 |
| S87 | 76 | @ad<="20040329" and 'ESD protection' same 'SOI' with 'bulk' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:15 |
| S88 | 40 | @ad<="20040329" and 'ESD protection' with 'SOI' with 'bulk' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:03 |
| S89 | 227 | @ad<="20040329" and 'SOI substrate' with 'bulk substrate' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:16 |
| S90 | 115 | @ad<="20040329" and 'CMOS' and 'SOI substrate' with 'bulk substrate' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:16 |
| S91 | 24 | @ad<="20040329" and 'CMOS' same 'SOI substrate' with 'bulk substrate' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:18 |
| S92 | 7 | @ad<="20040329" and 'CMOS' and 'SOI substrate' with 'bulk substrate' and 'ESD' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:18 |
| S93 | 44 | @ad<="20040329" and (361/56). ccls. and 'SOI' and 'ESD' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:50 |
| S94 | 114 | @ad<="20040329" and 'SOI' and 'ESD' and 'CMOS' and 'clamp' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:54 |

| S95 | 772 | @ad<="20040329" and 'ESD' and 'CMOS' and 'clamp' | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/06/07 11:54 |
|-----|-----|--------------------------------------------------|----------------------------------------------|----|----|--------------------|
| S96 | 1 | "6204537".PN. | USPAT; USOCR | OR | ON | 2005/06/07 12:02 |
| S97 | 1 | "6091592".PN. | USPAT; USOCR | OR | ON | 2005/06/07 12:02 |